

EAST Search History

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
S1	4	("20020152046") or ("20070112538") or ("5083364") or ("6745094").PN.	US-PGPUB; USPAT	OR	OFF	2008/04/07 13:36
S2	1303	(702/57-59).CCLS.	US-PGPUB; USPAT	OR	OFF	2008/04/07 13:36
S3	1124	(702/81-84).CCLS.	US-PGPUB; USPAT	OR	OFF	2008/04/07 13:36
S4	1059	(702/89,108).CCLS.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2008/04/07 13:36
S5	1190	(702/117).CCLS.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2008/04/07 13:36
S6	700	(702/118,119).CCLS.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2008/04/07 13:36
S7	860	(702/120,121,123,125).CCLS.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2008/04/07 13:36
S8	1347	(324/73.1).CCLS.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2008/04/07 13:36
S9	325	(324/500,537,754,765).ccls. and parametric adj test\$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/04/07 13:36
S10	62	(438/14,16,17).ccls. and parametric adj test\$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/04/07 13:36
S11	109	(438/14,16,17).ccls. and (concurrent\$2 simultaneous\$2 synchronous\$2 multitasking) with control	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/04/07 13:36
S12	1	(parametric and (test testing tested)).ti. and (load with wafer) same (automated or automatic\$)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/04/07 13:36

S13	146	parametric adj test\$3 and (concurrent\$2 simultaneous\$2 synchronous\$2 multitasking) with control	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/04/07 13:36
S14	91	parametric adj test\$3 and (concurrent\$2 simultaneous\$2 synchronous\$2 multitasking) with (controller controlling)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/04/07 13:36
S15	8	parametric adj test\$3 and (concurrent\$2 simultaneous\$2 synchronous\$2 multitasking) with ((wafer adj (loader positioner chuck)) (wafer adj tray adj loader) prober)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/04/07 13:36
S16	0	parametric adj test\$3 and synchronization\$3 with ((wafer adj (loader positioner chuck)) (wafer adj tray adj loader) prober)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/04/07 13:36
S17	0	parametric adj test\$3 and synchronization with ((wafer adj (loader positioner chuck)) (wafer adj tray adj loader) prober)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/04/07 13:36
S18	1	parametric adj test\$3 and ((wafer adj (loader positioner chuck)) (wafer adj tray adj loader) prober) same initializ\$3 near (data instrumentation instrument)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/04/07 13:36
S19	1	parametric adj test\$3 and ((wafer adj (loader positioner chuck)) (wafer adj tray adj loader) prober) same initializ\$3 near file	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/04/07 13:36
S20	4	parametric adj test\$3 and ((wafer adj (loader positioner chuck)) (wafer adj tray adj loader) prober) same load near test	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/04/07 13:36
S21	2	parametric adj test\$3 and ((prepare adj wafer) (move adj wafer) (move adj probe)) same initializ\$3 near (data instrumentation instrument)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/04/07 13:36
S22	0	parametric adj test\$3 and ((prepare adj wafer) (move adj wafer) (move adj probe)) same initializ\$3 near file	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/04/07 13:36
S23	6	parametric adj test\$3 and ((prepare adj wafer) (move adj wafer) (move adj probe)) same load near test	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/04/07 13:36
S24	6	parametric adj test\$3 and ((prepare adj wafer) (move adj wafer) (move adj probe)) same load near test	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/04/07 13:36

S25	0	parametric adj test\$3 and ((wafer adj (loader positioner chuck)) (wafer adj tray adj loader) prober same initialize\$3 near memory	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/04/07 13:36
S26	3	parametric adj test\$3 and state adj oscillator	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/04/07 13:36
S27	2	state adj oscillator same fault-tolerant same test\$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/04/07 13:36
S28	2	state adj oscillator same fault-tolerant	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/04/07 13:36
S29	33	state adj oscillator same test\$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/04/07 13:36
S30	2	state adj oscillator same state near module	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/04/07 13:36
S31	0	state adj oscillator same state near object	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/04/07 13:36
S32	10	state adj oscillator same control adj state	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/04/07 13:36
S33	2	state adj oscillator same superstate	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/04/07 13:36
S34	2	(wafer adj electrical adj (test testing)) with (move moving movement)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/04/07 13:36
S35	11	(semiconductor wafer) and (move moving movement prober alignment) with (simultaneous\$2 concurrent\$2) with (initialize initialized initialization)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/04/07 13:36
S36	14	parametric adj test\$3 and concurrent adj operation	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/04/07 13:36

S37	0	parametric adj test\$3 and simultaneous adj operation	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/04/07 13:36
S38	5	alignment with initialization with (concurrent\$2 simultaneous\$2)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/04/07 13:36
S41	1831	state adj oscillator	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/04/07 14:30
S42	693	state adj oscillator and control with state	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/04/07 14:30
S43	365	state adj oscillator and control with state and (semiconductor wafer integrated adj circuit)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/04/07 14:31
S44	73	fault adj tolerant with control with state	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/04/07 16:55

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